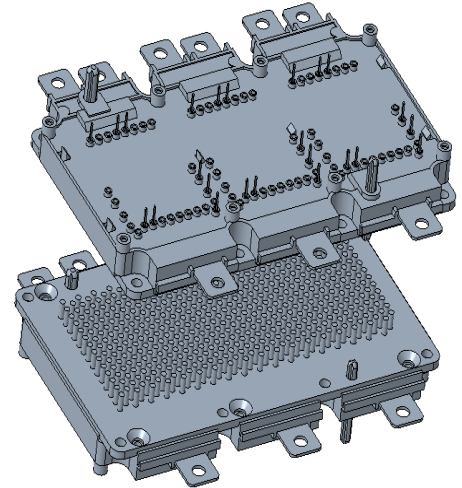




## HPD IGBT POWER MODULE

### CCGH950T75SD Trench-FS IGBT power module

$V_{CES}$	$V_{CEsat}$		$I_{CN}/I_{CRM}$
750V	$T_{vj}=25^{\circ}\text{C}@520\text{A}$	1.53V	950A/1900A
	$T_{vj}=175^{\circ}\text{C}@520\text{A}$	1.68V	



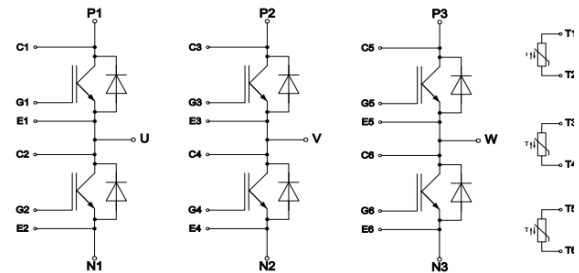
#### DESCRIPTION

This IGBT power module adopts a very compact six-pack (750V/950A) optimized for hybrid and electric vehicles. Due to the high clearance and creepage distances, the module is also well suited for increased system working voltages and supports modular inverter approaches.

#### FEATURES

- Increased blocking voltage to 750V
- Increased DC link Voltage
- High short circuit capability
- Self-limiting short circuit current
- High surge current capability
- High current density
- Ultra low conduction and switching loss
- Ultra-fast & soft recovery anti-parallel FRD
- Trench-FS IGBT technology
- High Power Density
- Emitter Controlled Diode
- Integrated NTC temperature sensor
- High creepage and clearance distances
- Direct cooled PinFin base plate
- Guiding elements for PCB and cooler assembly
- AQG324 Qualified

#### EQUIVALENT CIRCUIT



#### APPLICATIONS

- Motor Drives
- Hybrid Electrical Vehicles(H)EV
- Commercial Agriculture Vehicles
- Automotive applications

## CHARACTERISTICS VALUES

### MAXIMUM RATED VALUES(IGBT)

Parameter	Symbol	Conditions	Values	Units
Collector-emitter voltage	$V_{CES}$	$T_{vj}=25^{\circ}\text{C}$ , $V_{GE}=0\text{V}$	750	V
Implemented collector current	$I_{CN}$		950	A
Continuous DC collector current	$I_{C\text{ nom}}$	$T_F=95^{\circ}\text{C}$ , $T_{vj\text{ max}}=175^{\circ}\text{C}$	520 <sup>1)</sup>	A
Repetitive peak collector current	$I_{CRM}$	$t_p=1\text{ms}$ , $T_{vj}=25^{\circ}\text{C}$	1900	A
Gate-emitter peak voltage	$V_{GES}$	$T_{vj}=25^{\circ}\text{C}$	$\pm 30$	V
SC data	$I_{SC}$	$V_{GE}\leq 15\text{V}$ , $V_{CC}=400\text{V}$ $V_{CE\text{ max}}=V_{CES}-L_{sCE}\cdot di/dt$ $t_p\leq 5\mu\text{s}$ , $T_{vj}=150^{\circ}\text{C}$	4500	A
Total power dissipation	$P_{\text{tot}}$	$T_F=75^{\circ}\text{C}$ , $T_{vj\text{ max}}=175^{\circ}\text{C}$	769 <sup>1)</sup>	W

1) Verified by characterization / design not by test.

### CHARACTERISTICS VALUES(IGBT)

Parameter	Symbol	Conditions	Values			Units	
			Min.	Typ.	Max.		
Collector-emitter saturation voltage	$V_{CE\text{ sat}}$	$I_C=520\text{A}$ , $V_{GE}=15\text{V}$ , $T_{vj}=25^{\circ}\text{C}$		1.53	1.85	V	
		$I_C=520\text{A}$ , $V_{GE}=15\text{V}$ , $T_{vj}=150^{\circ}\text{C}$		1.65	2.1	V	
		$I_C=520\text{A}$ , $V_{GE}=15\text{V}$ , $T_{vj}=175^{\circ}\text{C}$		1.68	2.2	V	
Gate-emitter threshold voltage	$V_{GE\text{ th}}$	$V_{CE}=V_{GE}$ , $I_C=10\text{mA}$	$T_{vj}=25^{\circ}\text{C}$	5.0	6.1	7.0	V
			$T_{vj}=175^{\circ}\text{C}$		3.9		V
Gate charge	$Q_G$	$V_{GE}=-8\text{V}\dots+15\text{V}$ , $V_{CE}=400\text{V}$		4.3		$\mu\text{C}$	
Integrated gate resistor	$R_G$	$T_{vj}=25^{\circ}\text{C}$		1		$\Omega$	
Input capacitance	$C_{ies}$	$T_{vj}=25^{\circ}\text{C}$ , $f=1\text{MHz}$ , $V_{GE}=0\text{V}$ , $V_{CE}=50\text{V}$		37		nF	
Output capacitance	$C_{oes}$	$T_{vj}=25^{\circ}\text{C}$ , $f=1\text{MHz}$ , $V_{GE}=0\text{V}$ , $V_{CE}=50\text{V}$		0.88		nF	
Reverse transfer capacitance	$C_{res}$	$T_{vj}=25^{\circ}\text{C}$ , $f=1\text{MHz}$ , $V_{GE}=0\text{V}$ , $V_{CE}=50\text{V}$		0.25		nF	
Collector-emitter cut-off current	$I_{CES}$	$V_{CE}=750\text{V}$ , $V_{GE}=0\text{V}$	$T_{vj}=25^{\circ}\text{C}$			1	mA
			$T_{vj}=175^{\circ}\text{C}$		4		mA
Gate-emitter leakage current	$I_{GES}$	$V_{CE}=0\text{V}$ , $V_{GE}=20\text{V}$ , $T_{vj}=25^{\circ}\text{C}$			400	nA	
Turn-on delay time, inductive load	$t_{d\text{ on}}$	$I_C=520\text{A}$ , $V_{CE}=400\text{V}$ , $V_{GE}=-8\text{V}/+15\text{V}$ , $R_{G\text{ on}}=5\Omega$ , $R_{G\text{ off}}=5\Omega$	$T_{vj}=25^{\circ}\text{C}$		292		ns
			$T_{vj}=150^{\circ}\text{C}$		300		ns
			$T_{vj}=175^{\circ}\text{C}$		308		ns
Rise time, inductive load	$t_r$		$T_{vj}=25^{\circ}\text{C}$		78		ns
			$T_{vj}=150^{\circ}\text{C}$		89		ns
			$T_{vj}=175^{\circ}\text{C}$		92		ns
Turn-off delay time, inductive load	$t_{d\text{ off}}$		$T_{vj}=25^{\circ}\text{C}$		960		ns
			$T_{vj}=150^{\circ}\text{C}$		1073		ns
			$T_{vj}=175^{\circ}\text{C}$		1078		ns
Fall time, inductive load	$t_f$	$T_{vj}=25^{\circ}\text{C}$		48		ns	
		$T_{vj}=150^{\circ}\text{C}$		58		ns	
		$T_{vj}=175^{\circ}\text{C}$		70		ns	

Turn-on energy loss per pulse	E <sub>on</sub>	I <sub>C</sub> =520A, V <sub>CE</sub> =400V, V <sub>GE</sub> =-8V/+15V, R <sub>Gon</sub> =5Ω, R <sub>Goff</sub> =5Ω, L <sub>s</sub> =20nH, di/dt(T <sub>vj</sub> 25°)=5500A/μs, di/dt(T <sub>vj</sub> 150°)=5000A/μs, dv/dt(T <sub>vj</sub> 25°)=3100V/μs, dv/dt(T <sub>vj</sub> 150°)=2500V/μs	T <sub>vj</sub> =25°C	17.0	mJ
			T <sub>vj</sub> =150°C	28.1	mJ
			T <sub>vj</sub> =175°C	30.5	mJ
Turn-off energy loss per pulse	E <sub>off</sub>		T <sub>vj</sub> =25°C	33.2	mJ
			T <sub>vj</sub> =150°C	37.5	mJ
			T <sub>vj</sub> =175°C	38.2	mJ
IGBT, thermal resistance, junction to cooling fluid	R <sub>thjF IGBT</sub>	Per IGBT, ΔV/Δt=10 dm <sup>3</sup> /min, T <sub>F</sub> = 75°C		0.13	K/W

### MAXIMUM RATED VALUES(Diode)

Parameter	Symbol	Conditions	Values	Units
Repetitive peak reverse voltage	V <sub>RRM</sub>	T <sub>vj</sub> =25°C	750	V
Implemented forward current	I <sub>FN</sub>		950	A
Continuous DC forward current	I <sub>F</sub>		520 <sup>1)</sup>	A
Repetitive peak forward current	I <sub>FRM</sub>	t <sub>p</sub> =1ms	1900	A
I <sup>2</sup> t-value	I <sup>2</sup> t	V <sub>R</sub> =0V, t <sub>p</sub> =10ms, T <sub>vj</sub> =150°C	18500	A <sup>2</sup> s
		V <sub>R</sub> =0V, t <sub>p</sub> =10ms, T <sub>vj</sub> =175°C	15700	A <sup>2</sup> s

1) Verified by characterization / design not by test.

### CHARACTERISTICS VALUES(Diode)

Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Forward voltage	V <sub>F</sub>	I <sub>F</sub> =520A, V <sub>GE</sub> =0V	T <sub>vj</sub> =25°C	1.70	1.90	V
			T <sub>vj</sub> =150°C	1.73		V
			T <sub>vj</sub> =175°C	1.75		V
Peak reverse recovery current	I <sub>RM</sub>	I <sub>F</sub> =520A, V <sub>R</sub> =400V, V <sub>GE</sub> =-8V -di <sub>F</sub> /dt=5000A/μs (T <sub>vj</sub> =150°C)	T <sub>vj</sub> =25°C	230		A
			T <sub>vj</sub> =150°C	340		A
			T <sub>vj</sub> =175°C	360		A
Recovered charge	Q <sub>r</sub>	I <sub>F</sub> =520A, V <sub>R</sub> =400V, V <sub>GE</sub> =-8V -di <sub>F</sub> /dt=5000A/μs (T <sub>vj</sub> =150°C)	T <sub>vj</sub> =25°C	19.4		μC
			T <sub>vj</sub> =150°C	38.5		μC
			T <sub>vj</sub> =175°C	43.6		μC
Reverse recovery energy	E <sub>rec</sub>	I <sub>F</sub> =520A, V <sub>R</sub> =400V, V <sub>GE</sub> =-8V -di <sub>F</sub> /dt=5000A/μs (T <sub>vj</sub> =150°C)	T <sub>vj</sub> =25°C	3.7		mJ
			T <sub>vj</sub> =150°C	6.6		mJ
			T <sub>vj</sub> =175°C	7.3		mJ
Diode, thermal resistance, junction to cooling fluid	R <sub>thjF Diode</sub>	Per diode, ΔV/Δt = 10 dm <sup>3</sup> /min, T <sub>F</sub> = 75°C		0.17	K/W	

### NTC-THERMISTOR

Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Rated resistance	R <sub>25</sub>	T <sub>C</sub> =25°C		5.0		KΩ
Deviation of R100	ΔR/R	T <sub>C</sub> =100°C, R <sub>100</sub> =493Ω	-3		3	%
Power dissipation	P <sub>25</sub>	T <sub>C</sub> =25°C			60	mW
B-value	B <sub>25/50</sub>	R <sub>2</sub> =R <sub>25</sub> exp[B <sub>25/50</sub> (1/T <sub>2</sub> -1/(298.15K))]		3375		K
B-value	B <sub>25/80</sub>	R <sub>2</sub> =R <sub>25</sub> exp[B <sub>25/80</sub> (1/T <sub>2</sub> -1/(298.15K))]		3411		K
B-value	B <sub>25/100</sub>	R <sub>2</sub> =R <sub>25</sub> exp[B <sub>25/100</sub> (1/T <sub>2</sub> -1/(298.15K))]		3433		K

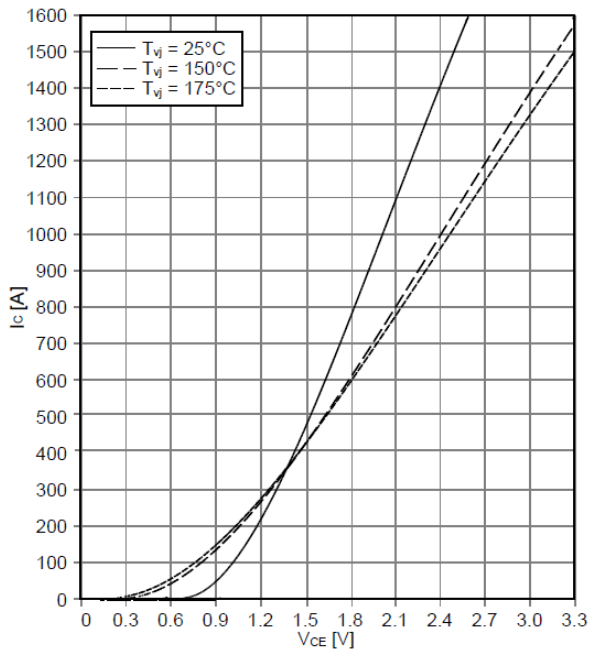
## MODULE

Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Maximum junction temperature	$T_{vj\ max}$				175	°C
Temperature under switching conditions	$T_{vj\ op}$		-40		175	°C
Storage temperature	$T_{stg}$		-40		150	°C
Stray inductance module	$L_{sCE}$			7		nH
Module lead resistance, terminals-chip	$R_{CC+EE}$	$T_{vj}=25^{\circ}C$ , per switch		0.72		mΩ
Isolation test voltage	$V_{isol}$	AC, RMS, f=50Hz, t=1min		3.5		kV
Creepage distance	ds	Terminal to terminal		9.0		mm
		Terminal to base		9.0		mm
Clearance distance in air	da	Terminal to terminal		4.5		mm
		Terminal to base		4.5		mm
Comperative tracking index	CTI		>200			
Mounting torque for module mounting	M1	Screw M4 baseplate to heatsink	1.8	2.0	2.2	N·m
	M2	Screw M4 EJOT Delta PCB to frame	0.45	0.50	0.55	
Terminal connection torque	M3	Screw M5	3		6	
Internal isolation	-	Basic insulation (class1, IEC 61140)	AlN			-
Material of module baseplate	-		Cu+Ni			-
Dimensions	L x W x H		154.5x126.5x32			mm
Weight	G		720			g

# CHARACTERISTICS DIAGRAMS

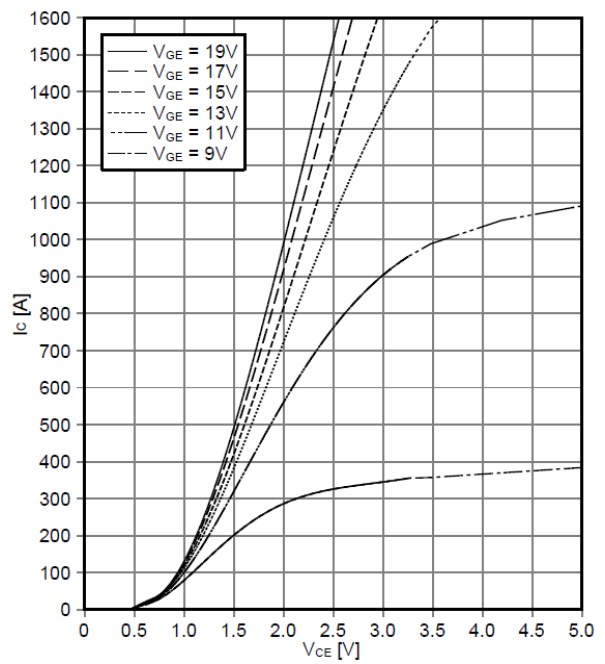
**Output characteristic IGBT, Inverter(typical)**

$I_C=f(V_{CE}), V_{GE}=15V$



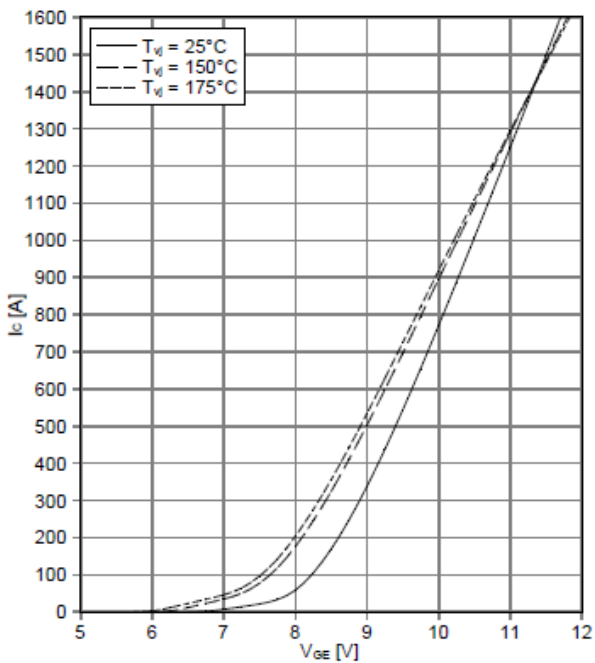
**Output characteristic IGBT, Inverter(typical)**

$I_C=f(V_{CE}), T_{vj}=150^\circ C$



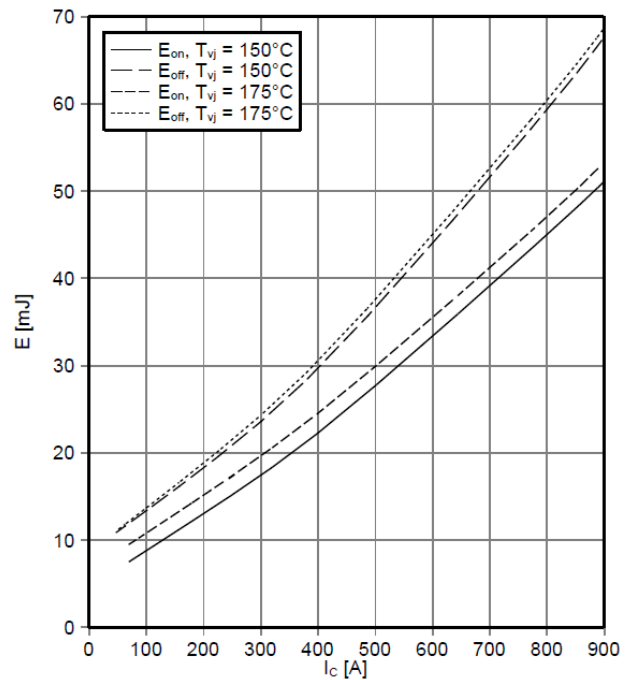
**Transfer characteristic IGBT, Inverter(typical)**

$I_C=f(V_{GE}), V_{CE}=20V$



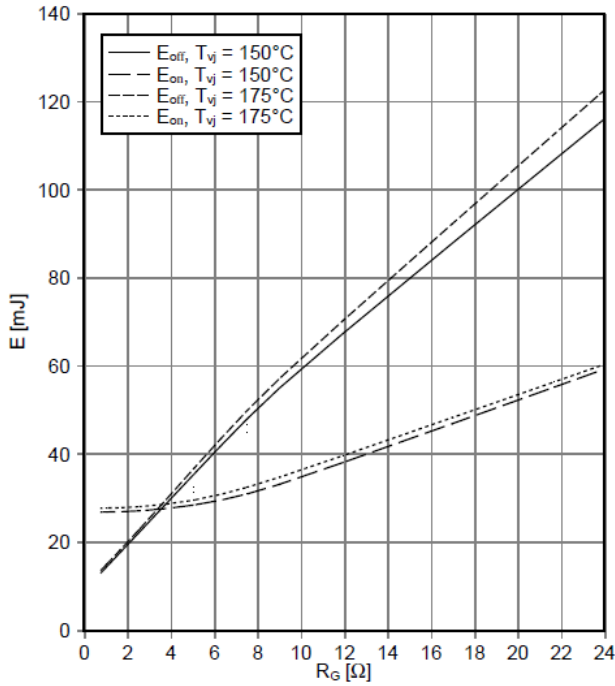
**Switching losses IGBT, Inverter(typical)**

$E_{on}=f(I_C), E_{off}=f(I_C) V_{GE}=-8V/+15V, R_{Gon}=5\Omega, R_{Goff}=5\Omega, V_{CE}=400V$



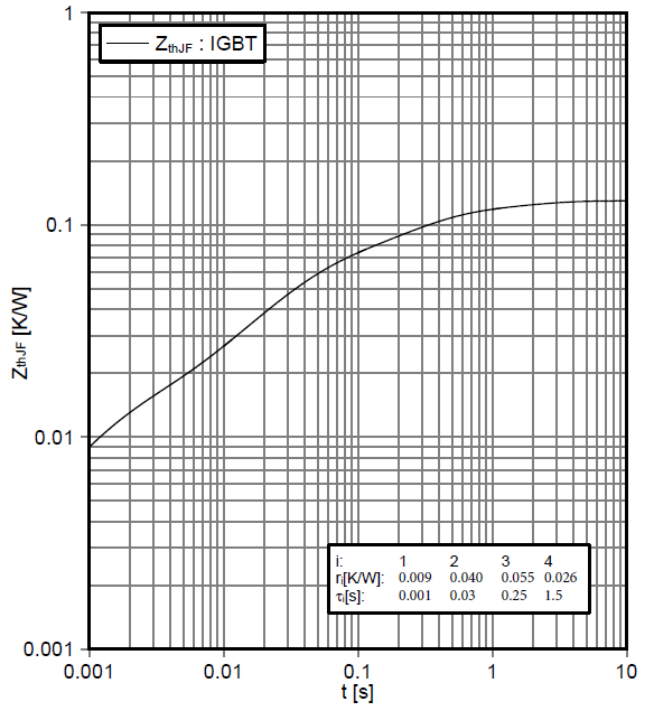
**Switching losses IGBT, Inverter(typical)**

$E_{on}=f(R_G)$ ,  $E_{off}=f(R_G)$   $V_{GE}=-8V/+15V$ ,  $I_C=520A$ ,  $V_{CE}=400V$



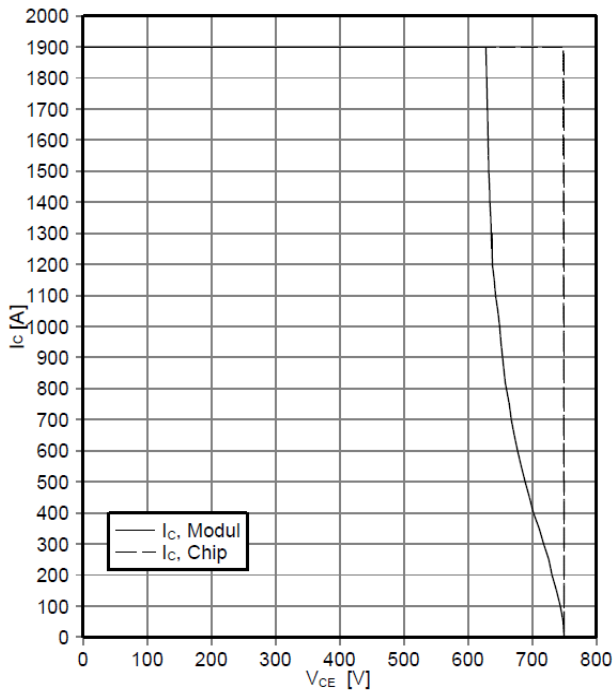
**Transient thermal impedance IGBT, Inverter**

$Z_{thJF}=f(t)$



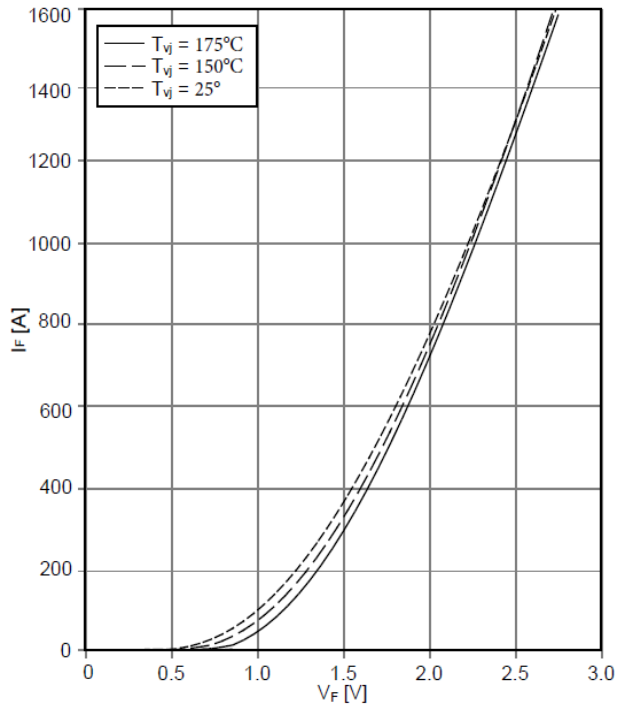
**Reverse bias safe operating area IGBT, Inverter(RBSOA)**

$I_C=f(V_{CE})$ ,  $V_{GE}=\pm 15V$ ,  $R_{Goff}=5\Omega$ ,  $T_{vj}=150^\circ C$



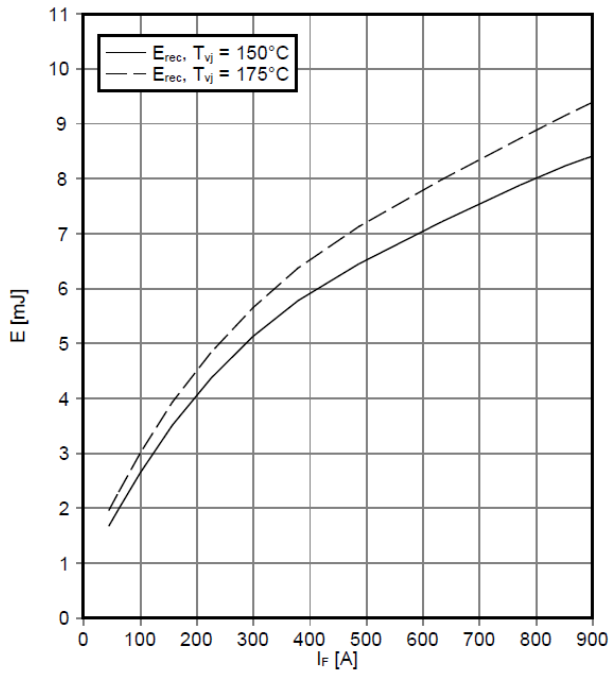
**Forward characteristic of Diode, Inverter(typical)**

$I_F=f(V_F)$



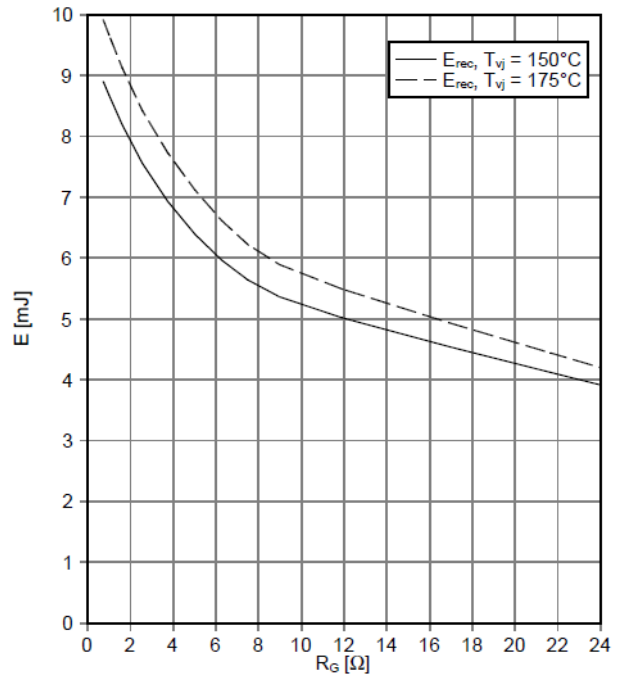
**Switching losses Diode, Inverter(typical)**

$E_{rec}=f(I_F), R_{Gon}=5\Omega, V_{CE}=400V$



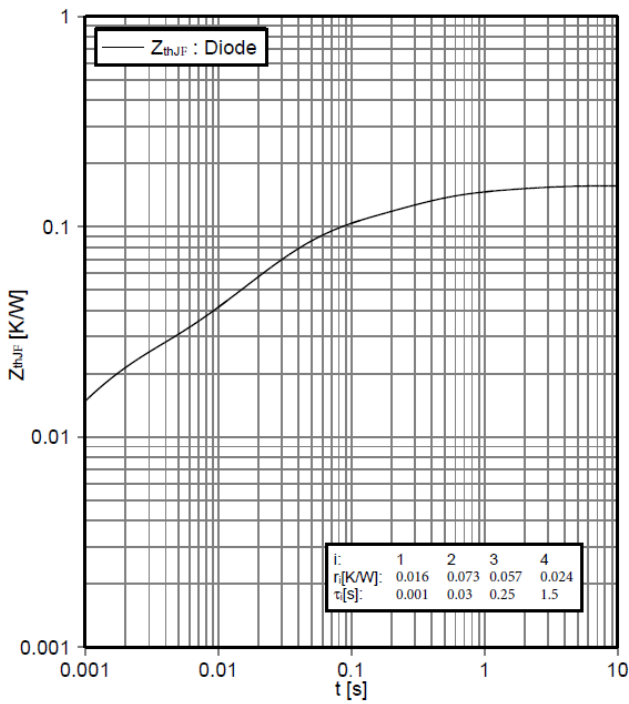
**Switching losses Diode, Inverter(typical)**

$E_{rec}=f(R_G), I_F=450A, V_{CE}=400V$



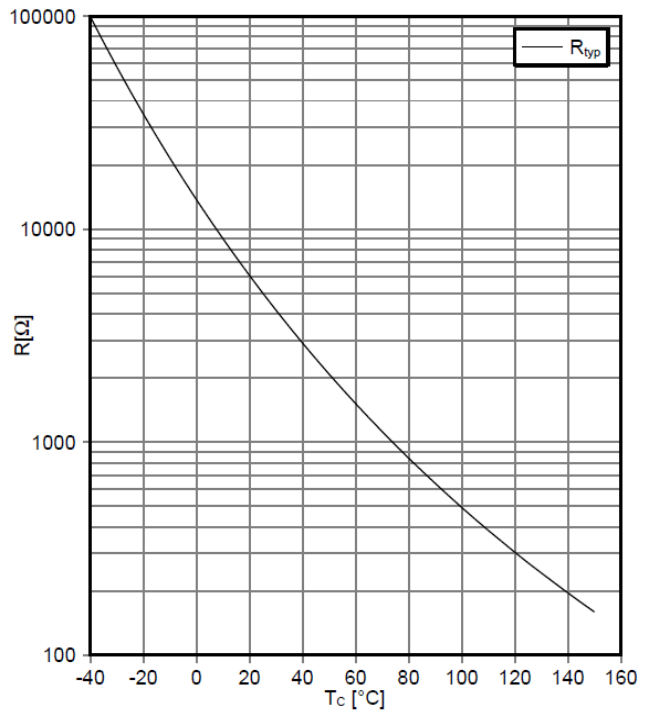
**Transient thermal impedance Diode, Inverter**

$Z_{thJF}=f(t)$

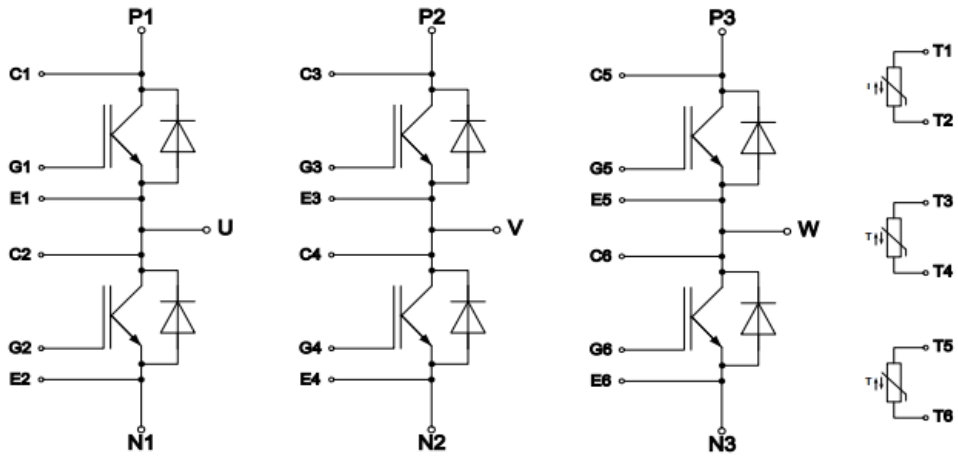


**NTC-Thermistor-temperature, characteristic(typical)**

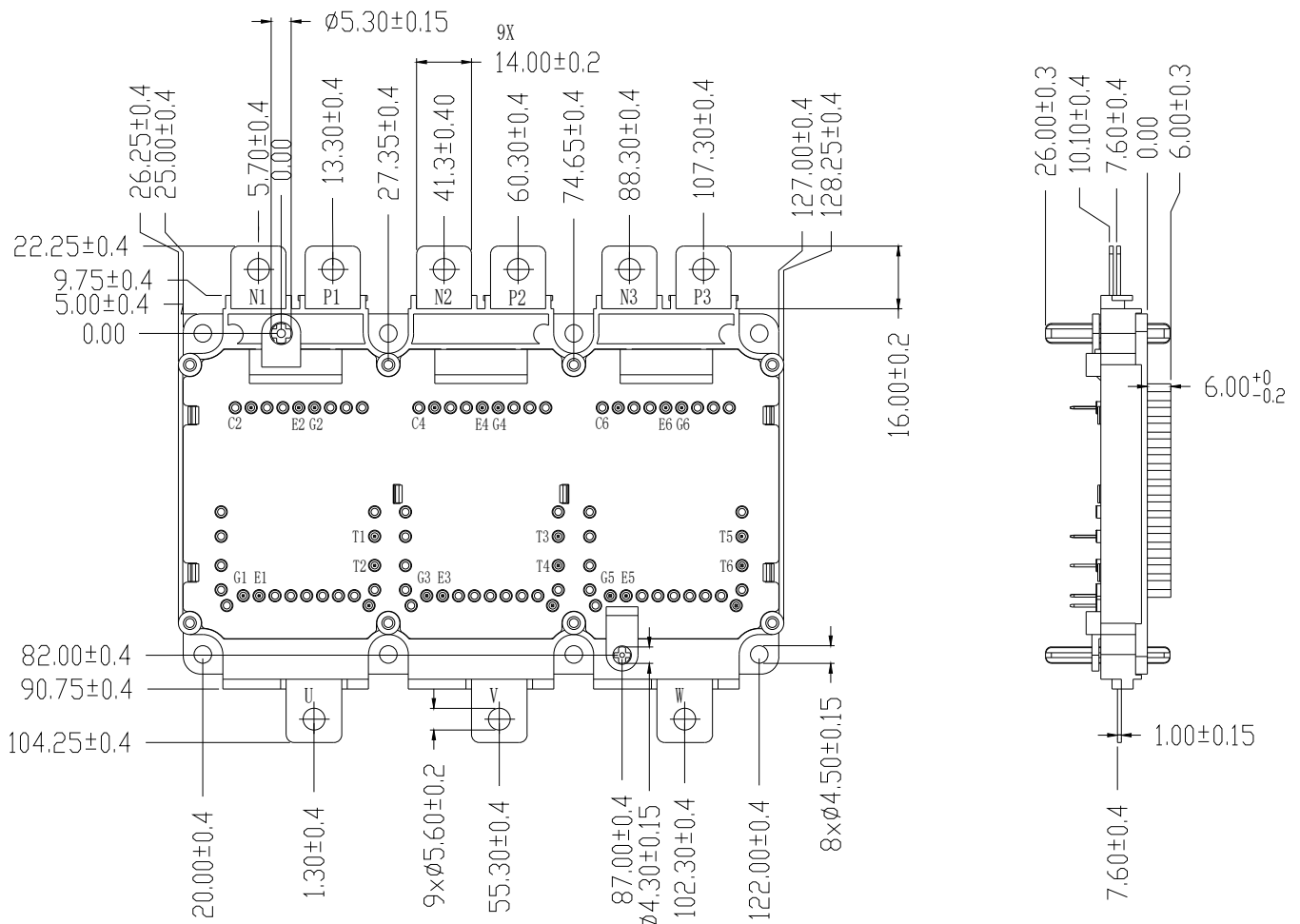
$R=f(T)$



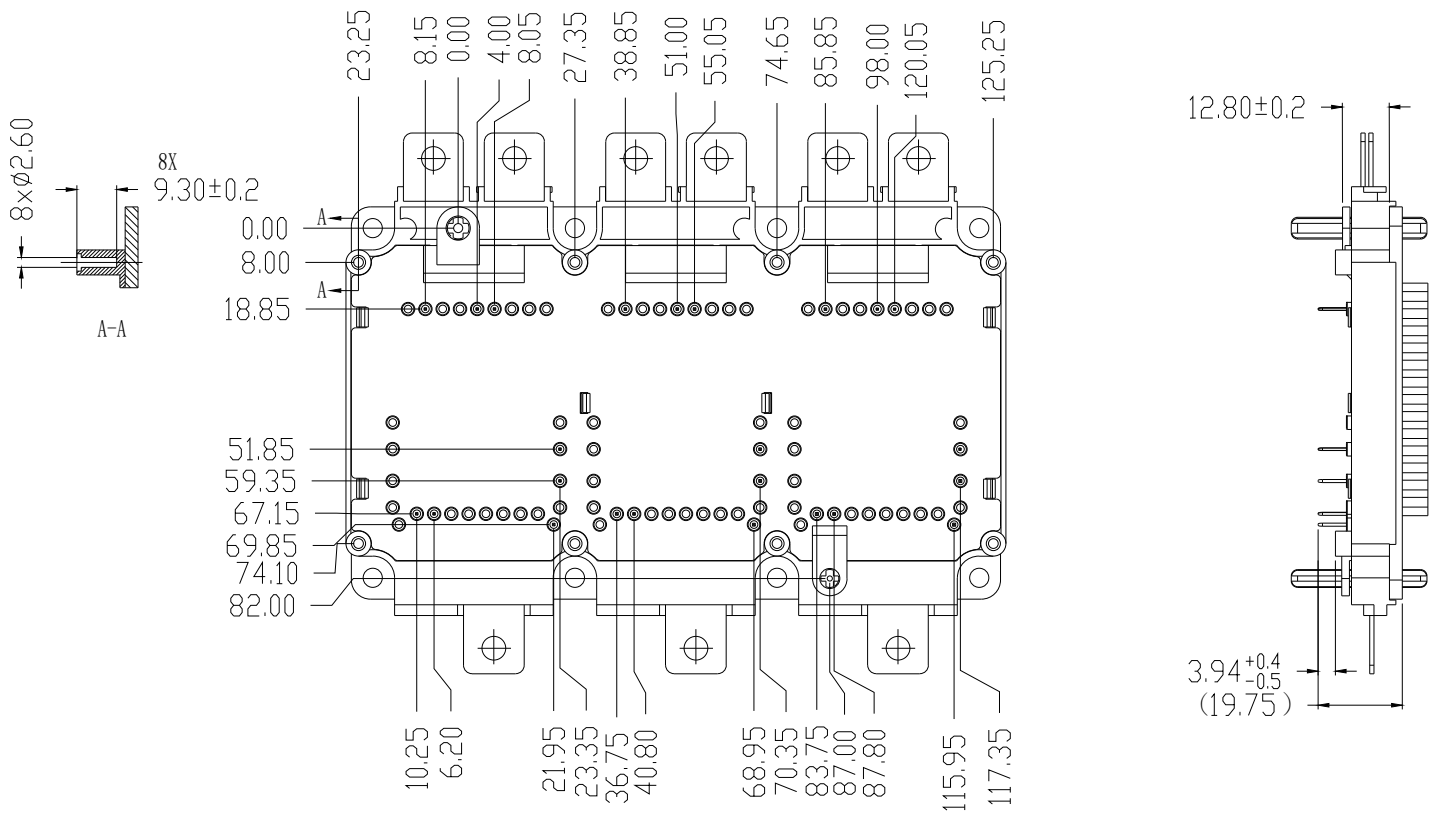
## CIRCUIT DIAGRAM



## PACKAGE OUTLINES







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Date of change	Rev #	revise content
2023/04/21	A/0	Initial releases